Notice of References Cited Application/Control No. 10/540,051 Examiner Andrew C. Lee Applicant(s)/Patent Under Reexamination TIAN ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-7,164,671	01-2007	del Prado et al.	370/338
*	В	US-6,990,116	01-2006	Young et al.	370/445
*	C	US-2005/0002373	01-2005	Watanabe et al.	370/346
*	D	US-7,221,681	05-2007	Choi et al.	370/447
*	Е	US-2002/0071449	06-2002	Ho et al.	370/447
*	F	US-7,289,529	10-2007	Sherman, Matthew J.	370/461
*	G	US-2006/0041676	02-2006	Sherman, Matthew J.	709/231
*	Η	US-2006/0029073	02-2006	Cervello et al.	370/389
*	I	US-7,058,074	06-2006	Ho et al.	370/447
*	J	US-2006/0040709	02-2006	Adachi et al.	455/562.1
*	К	US-2002/0154653	10-2002	Benveniste, Mathilde	370/447
*	L	US-2003/0174665	09-2003	Benveniste, Mathilde	370/317
*	М	US-7,016,948	03-2006	Yildiz, Kazim Orhan	709/221

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Ø					
	R					
	Ø					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	w	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.